

**Search Notes**

Application No.

10/608,883

Examiner

Stephen W. Smoot

Applicant(s)

AVANZINO ET AL.

Art Unit

2813

**SEARCHED**

Class	Subclass	Date	Examiner
257	751	5/25/2004	SWS
257	752	5/25/2004	SWS
257	759	5/25/2004	SWS
257	760	5/25/2004	SWS
257	762	5/25/2004	SWS
Updated	Above	11/5/2004	SWS

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Considered all citations from parent applications.	5/25/2004	S.W.S. SWS
Key Words: Damascene Structure - Inlaid, Copper, Electroplated, Seed Layer;	5/25/2004	S.W.S. SWS
Interlayer Dielectric - SiCOH, MSQ; Insulating Barrier - SiCH.	5/25/2004	S.W.S. SWS
Updated Above Search	11/5/2004	S.W.S. SWS
Search Tools - EAST (attached): USPAT; US PG PUBS; Derwent; EPO; JPO; IBM TDB	5/25/2004 8 11-5-04	SWS S.W.S.